## Application/Control No. Applicant(s)/Patent Under Reexamination 10/028,145 LEE ET AL. Notice of R ferences Cited Examiner Art Unit Page 1 of 1

3745

## **U.S. PATENT DOCUMENTS**

Christopher Verdier

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name .	Classification
	Α	US-3423069-A	01-1969	Chandley	416/92
	В	US-4501053-A	02-1985	Craig et al.	416/97R
	С	US-6164914-A	12-2000	Correia et al.	416/97R
	D	US-5733102-A	03-1998	Lee et al.	416/97R
	Ε	US-6224336-B1	05-2001	Kercher	416/97R
	F	US-2002/0187044-A1	12-2002	Lee et al.	416/97R
	G	US-6224337-B1	05-2001	Lieland et al.	416/97R
	н	US-			•
	ı	US-			,
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*	Ü	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-1-53002-A	03-1989	Japan		416/95
	0					
	P.					
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

_	г —	
*	١.	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.